



Scaling up fault injection simulation campaigns

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- French offensive security company
- 180+ security experts
- 5 departments:
 - Pentest / Redteam
 - RE / VR
 - Development
 - Incident Response
 - Revel.io

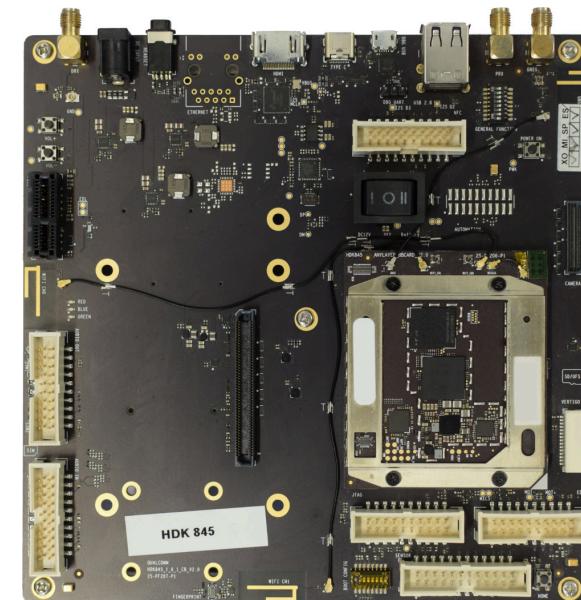
Introduction

Goal: Running unsigned code on a smartphone with configured secure boot. Target the boot ROM.

Qualcomm SDM845 System-on-Chip, 2018
Boot ROM dumped using devboard JTAG.

Problems:

- Modern SoC
- Large boot ROM (~200 kB)
- Package-on-Package: DRAM stacked on SoC



Prior work on older SoC

The image consists of two parts. On the left, a photograph of a man speaking on stage at a conference. He is wearing a dark suit and a lanyard. The background is a large screen displaying the Black Hat Europe 2022 logo and some text. On the right, a screenshot of a presentation slide. The slide has a dark background with lightning bolt graphics. At the top, it says 'black hat EUROPE 2022'. Below that is a video player showing the same speaker from the photograph. To the right of the video player, the title 'Motivation & Goals' is displayed in yellow. Underneath, there is a section titled 'About this Talk' and two main bullet points: 'Main goals' and 'Device Under Test'. To the right of the 'Device Under Test' section is a small image of a printed circuit board (PCB) labeled 'DragonBoard 410c'. At the bottom of the slide, there is a blue footer bar with the text 'CYBER INTELLIGENCE', the date 'DECEMBER 5-8, 2022', the location 'EXCEL LONDON / UK', and social media handles '@BHEU @BlackHatEvents'.

Motivation & Goals

About this Talk

- Main goals
 - Bypass the Secure Boot of a real hardware (BFU) using VCC Glitching.
 - Run Arbitrary code with maximum privileges (EL3).
 - Provide a generic method that does not require reversing engineering.
- Device Under Test:
 - We started with a device we can enable secure boot (have the keys!)
 - **Board:** DragonBoard 410c
 - **Soc:** MSM8916/APQ8016

CYBER INTELLIGENCE

DECEMBER 5-8, 2022

EXCEL LONDON / UK

Hector Marco, BlackHat Europe 2022

Side-channel divergence and power glitching: secure boot bypass on Qualcomm **MSM8916** (2014).

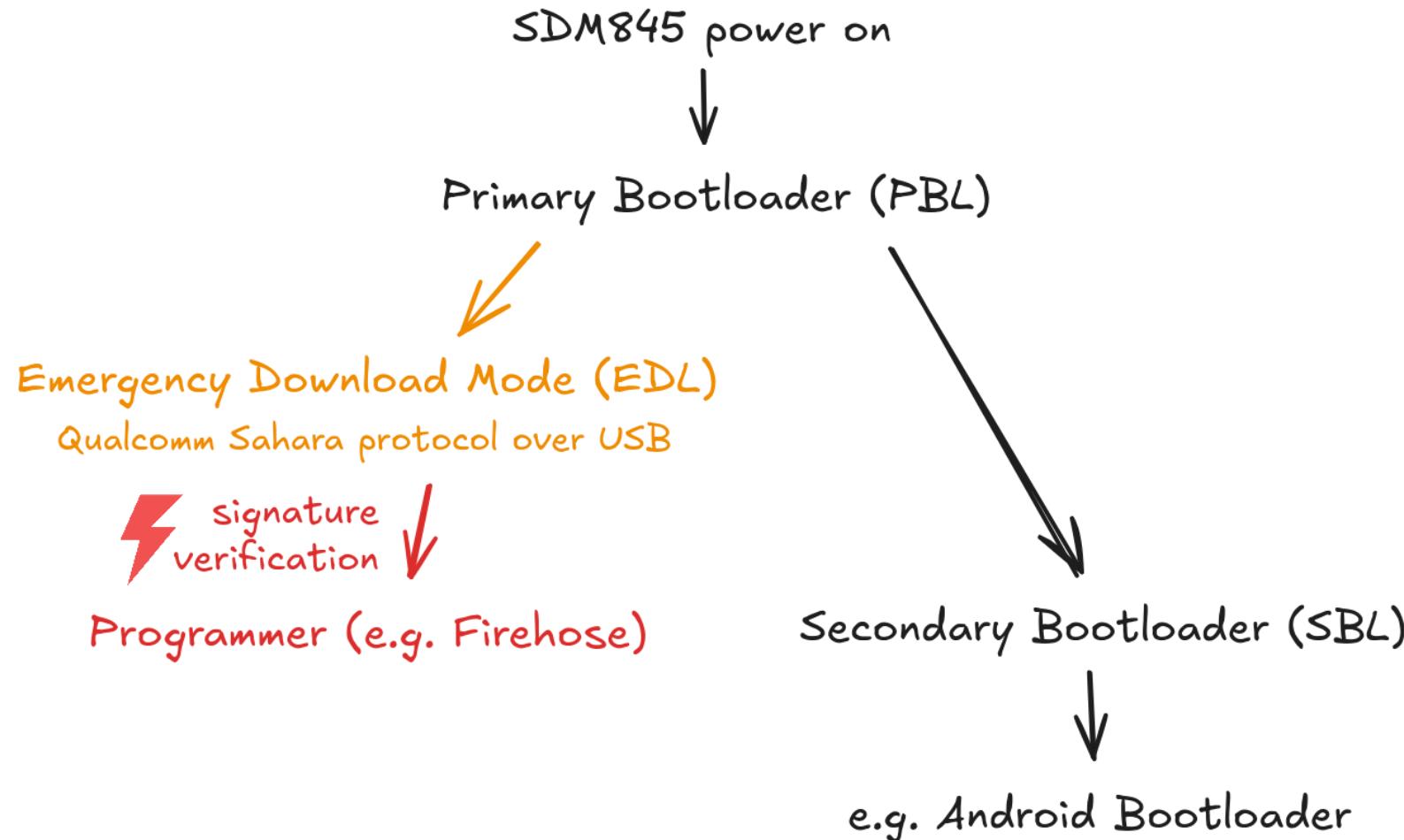
Planning

1. Fault injection **simulation** (with optimisations) on SDM845 boot ROM
2. **Simulation to reality** mapping
3. **Real-world** fault injection campaign and failures

Fault injection simulation

and optimisations

Fault injection target



Fault injection target

Same scenario as MSM8916 BlackHat talk:

- Programmer is a ELF file with a segment containing a certificate chain.
- Signature verifications chain:
 1. Fused public key
 2. Root CA certificate
 3. Attestation CA certificate
 4. Loader certificate
 5. Hash table signature

Target: bypass Root CA certificate signature verification.

Fault injection simulation

Python tool based on Unicorn-Engine: <https://github.com/Ledger-Donjon/rainbow/>

```
emu = rainbow_aarch64()
emu.load("bootrom.elf")
emu.hook_bypass("generate_random", lambda e: e[e["x0"]] = random.randbytes(e["x1"]))
emu.start(0x08000000, 0, count=1000)
fault_skip(emu) # inject fault after 1000 instructions
emu.start(emu["pc"], 0)
```

Alternative with QEMU TCG: <https://github.com/erdnaxe/qemu-fault-plugins>

```
qemu-system-arm -machine netduinoplus2 -nographic -d plugin \
    -drive if=none,format=qcow2,file=snapshot.qcow2 -loadvm snapshot \
    -plugin libstoptrigger.so,addr=0x08001235,addr=0x08004019:129,icount=4000000:130 \
    -plugin libskipinsn.so,icount=1000
```

Simulation optimisation #1

Lazy: start simulation from reset address

Consequence: simulation ETA is >3 years

First low-hanging fruits: cut "bad-code" flows early by replacing them with `BRK #0`.

Some bad code paths to patch:

- `BL #0` instructions (can be automatically replaced)
- USB error handlers

Simulation optimisation #2

Observations:

- Counting instructions can be slow (GDB protocol, QEMU TCG scoreboard)
- Breakpoints on addresses is more robust (survive small hooking changes)
- Emulation must be deterministic for a fault injection campaign to make sense

Solution: record an execution trace and use it as a reference for fault campaigns

Execution trace contains list of:

```
struct basic_block_info {
    uint64_t address;
    uint32_t current_cpu;
    uint32_t instructions_count;
    uint8_t  instructions_size[instructions_count];
};
```

This trace can be processed to find blocks executed only once, and fault them first.

Fault by `(address, execution_count)`

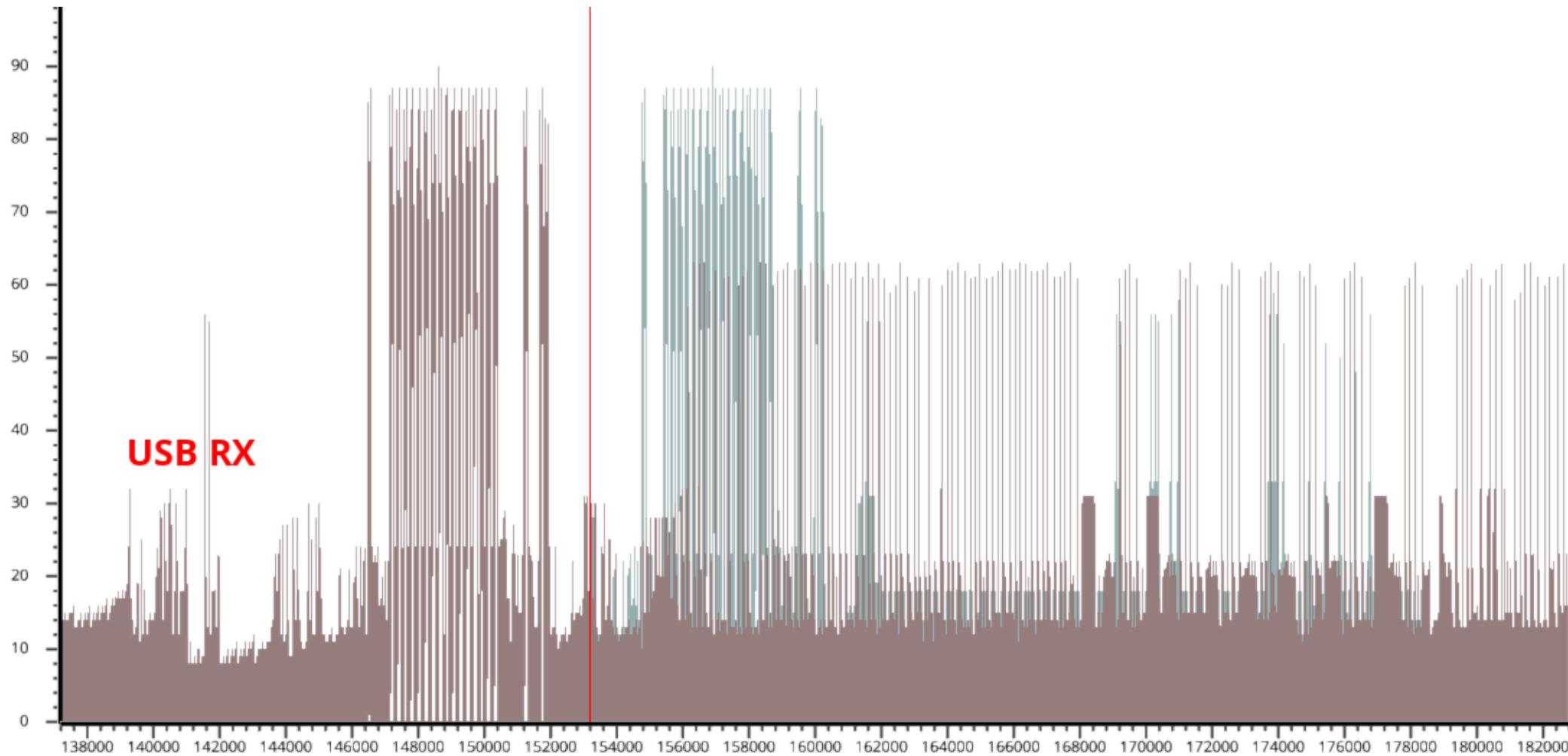
Simulation results

| Fault model | ✓ Bypass | ⚠ Error detected | ⚡ Crash |
|--|---|------------------|--------------|
| Single instruction skip | 0x0031E688:0 0x0031F060:1 0x0031F064:1 0x0031F08C:1 ... (25 total) | 420+1957 total | 17624+ total |
| Stuck destination register at 0x00000000 | 0x0031F060:1 0x0031F064:1 | 23+277 total | 5861+ total |
| Stuck destination register at 0xFFFFFFFF | 0x0031F064:1 | 5+142 total | 14484+ total |

Target: second execution at address **0x0031F064**

Static analysis: **0x0031F064** seems related to reading fuses

Side-channel simulation



Hamming Weight of the destination register, relative to the instruction count

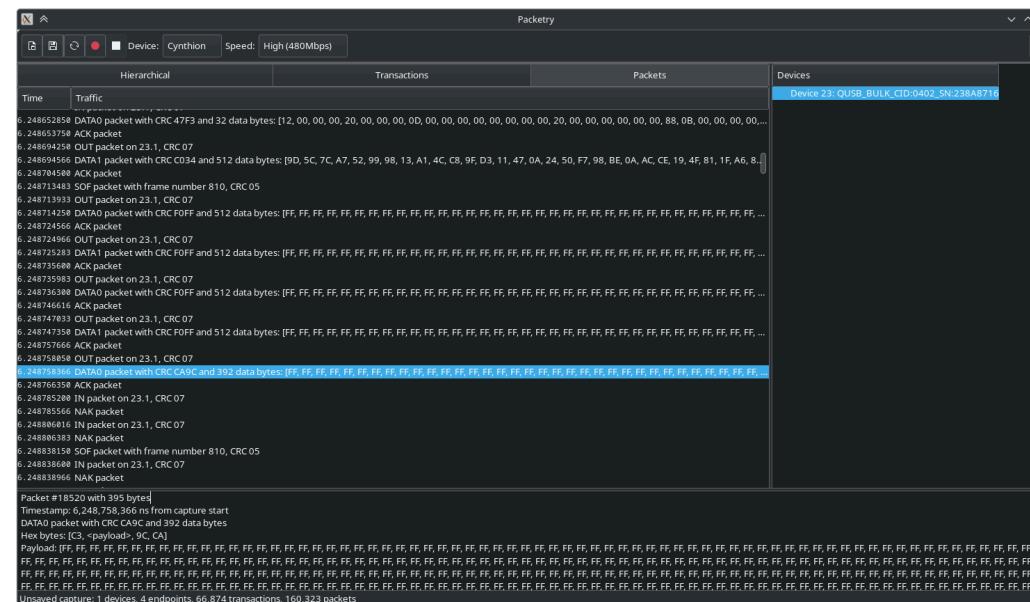
Simulation to reality mapping

USB triggering

Problem: need a hardware trigger as a reference for faults injection

Simulation conclusion: fault after the last packet of the loader hash table segment

Solution: modify Cynthion USB analyser to raise a trigger on the USB packet



Side-Channel Analysis

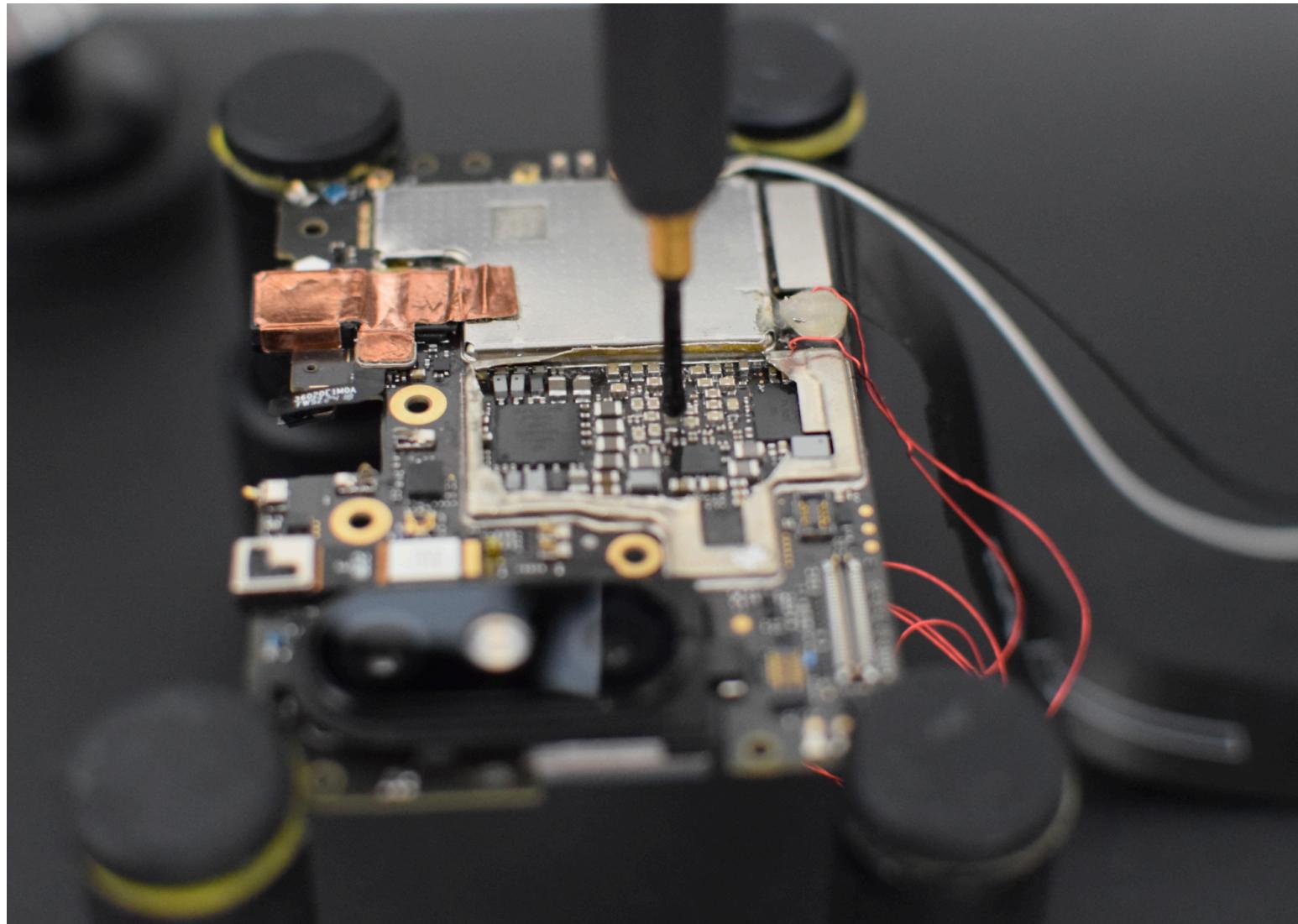
Problem: need side-channel traces to match fault simulation patterns

Smartphone: Xiaomi Mi 8, PCB boardview, schematics and EDL loader are leaked online

Power rails identification (behind SoC):

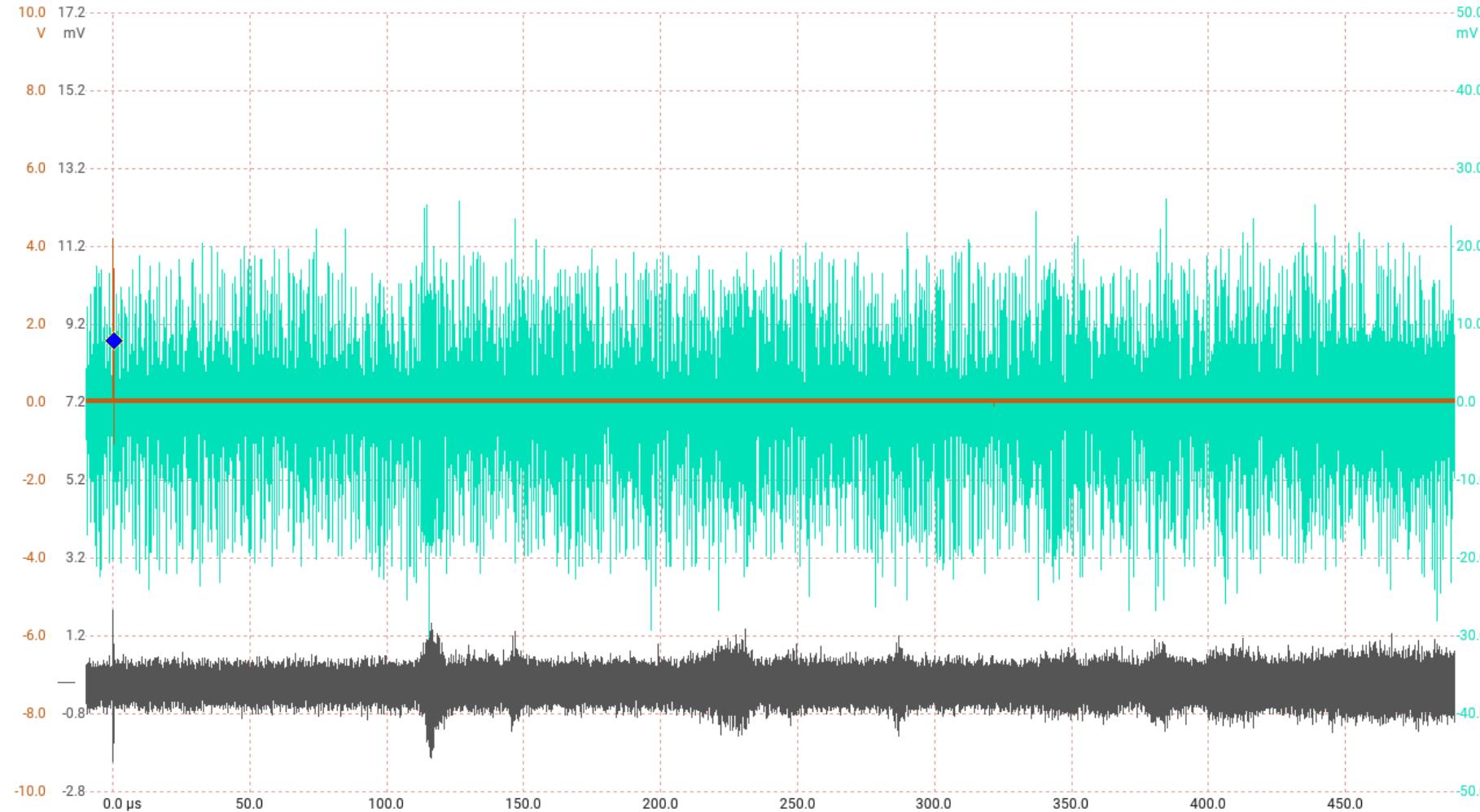
- PM845 - Power Management IC for SDM845
- **VDD_AP0** - Application Processor Core 0 power domain
- VDD_AP1 - Application Processor Core 1 power domain, **off during boot**
- VDD_CX - Digital power domain directly supplied by Core crystal oscillator (CXO)
- VDD_MX - Memory power domain

Side-Channel Analysis



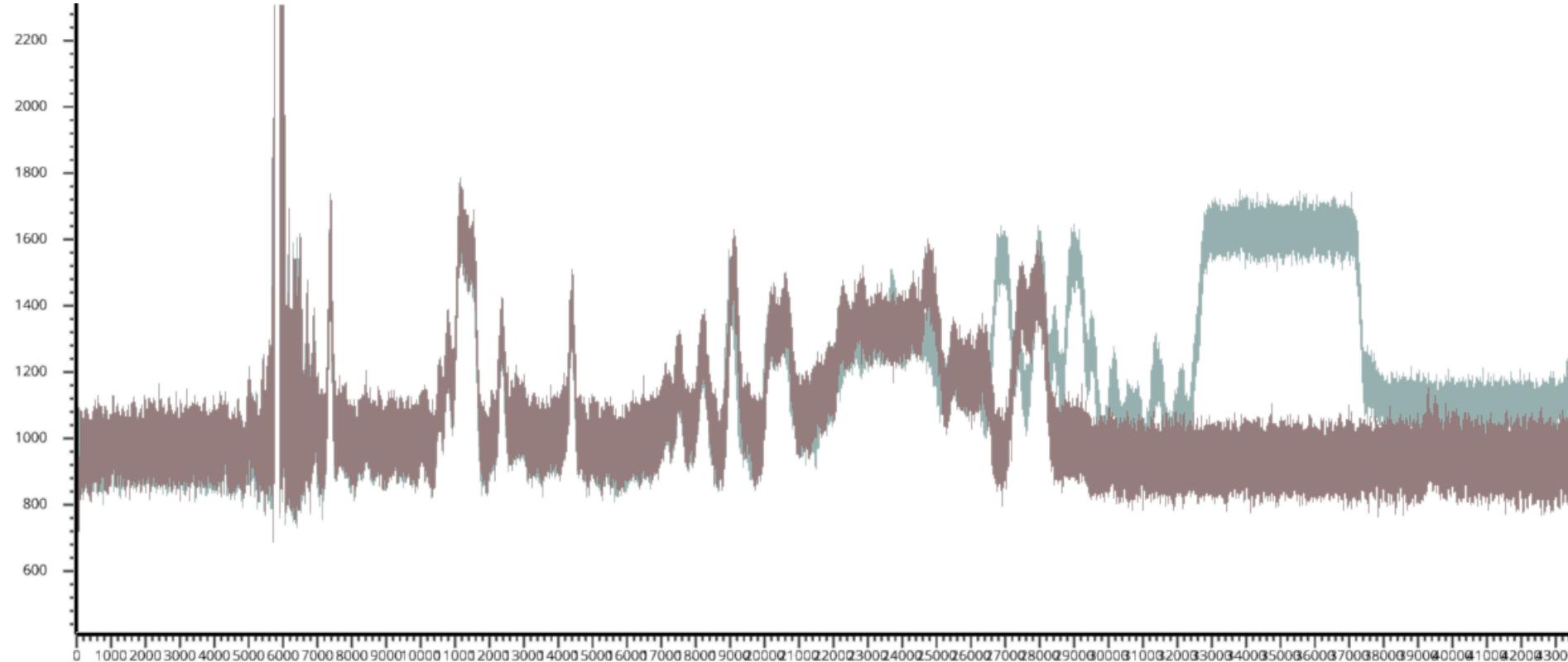
Side-Channel Analysis

Some patterns emerge from averaging without any post-processing!

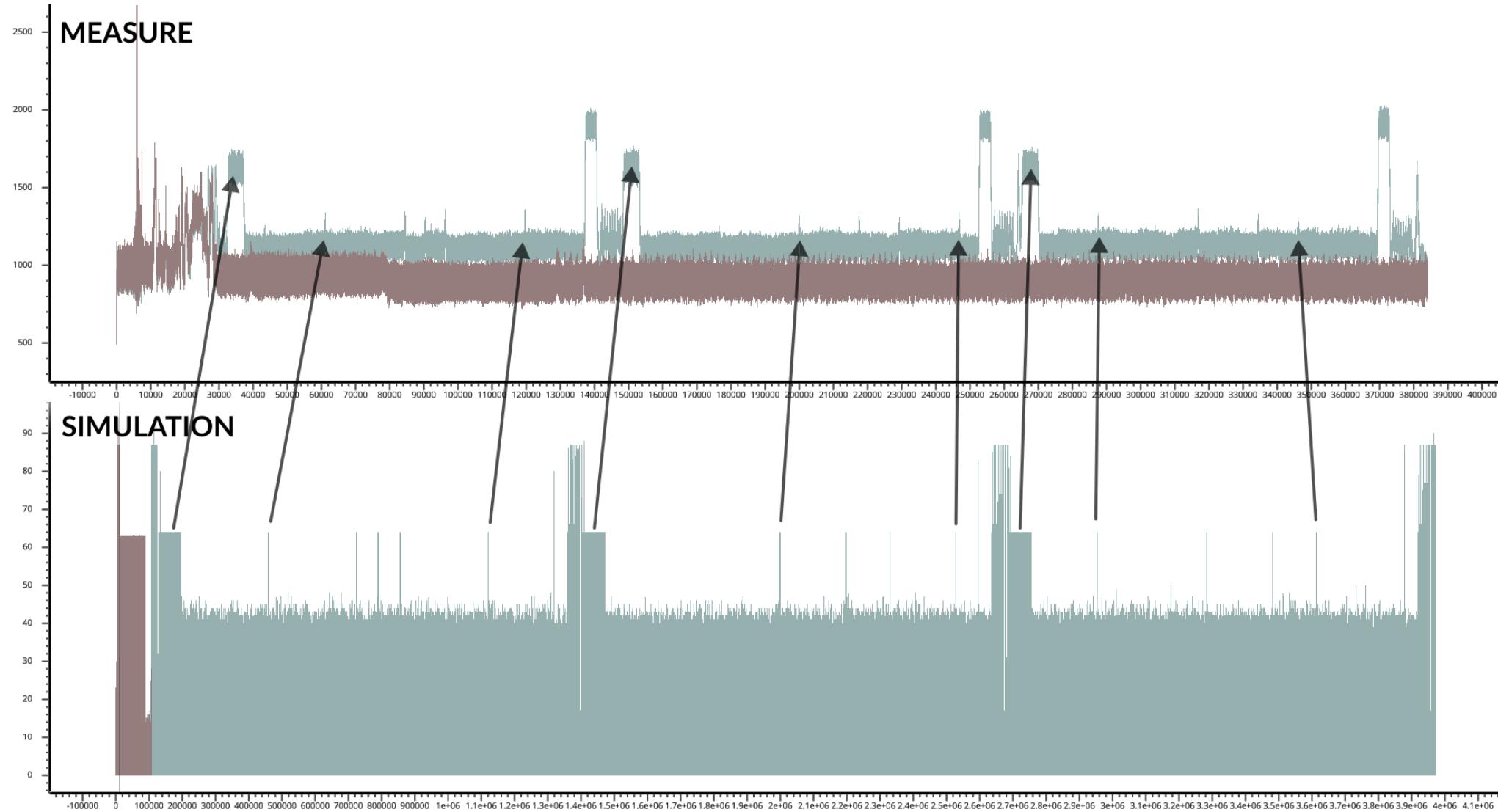


Side-Channel Analysis

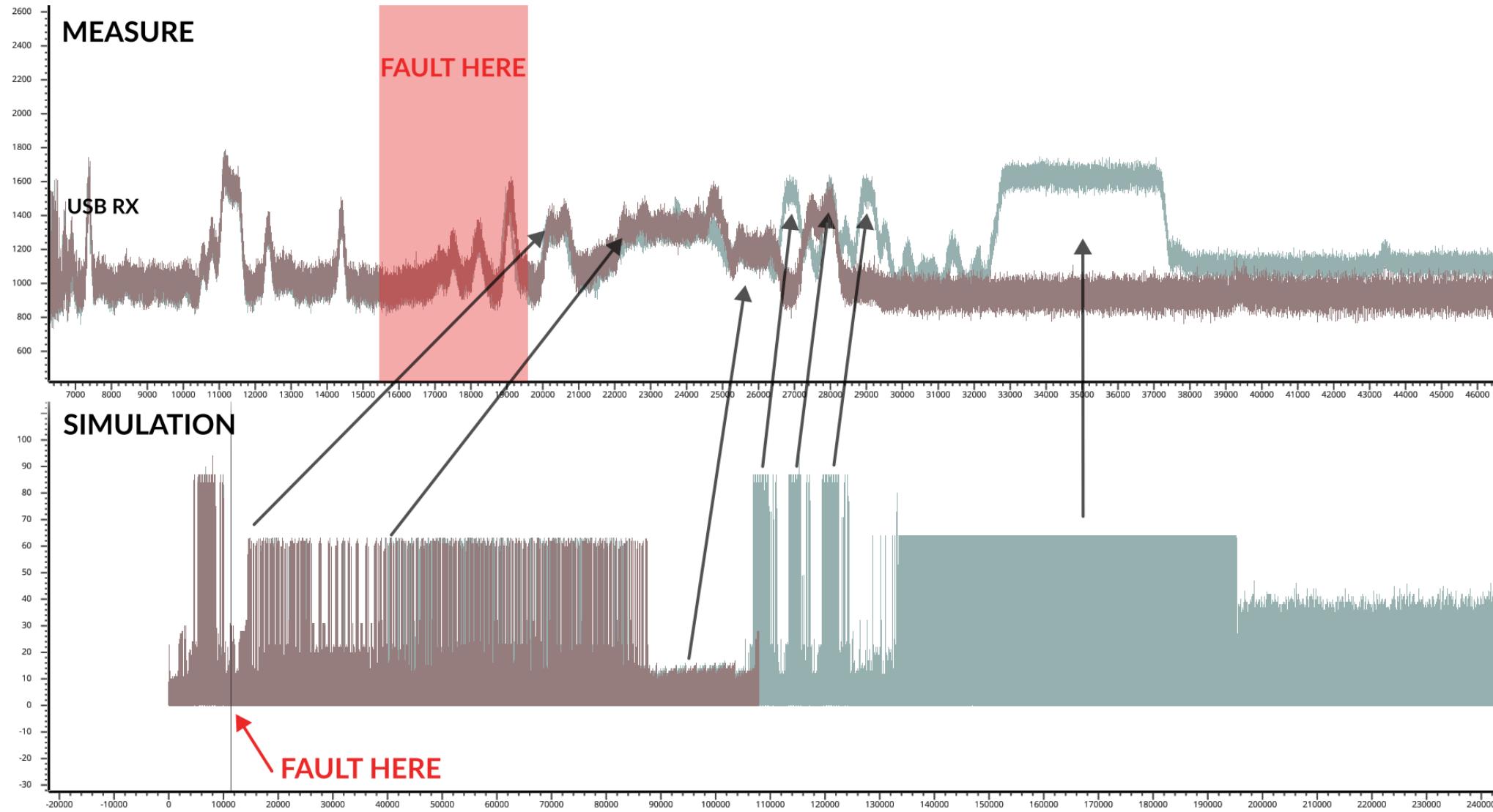
Average of 1000 synced traces



Simulation mapping



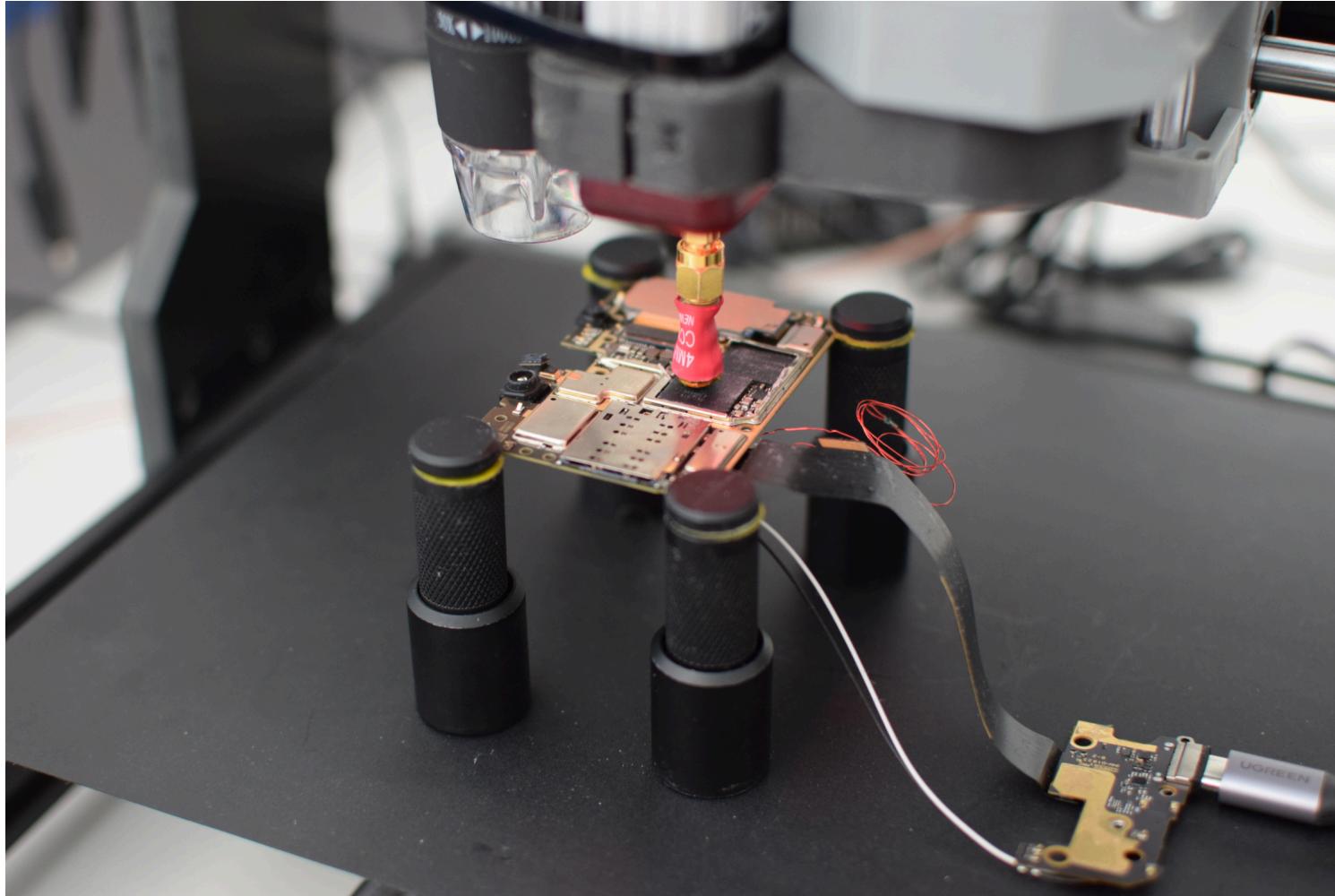
Simulation mapping



Fault injection campaign

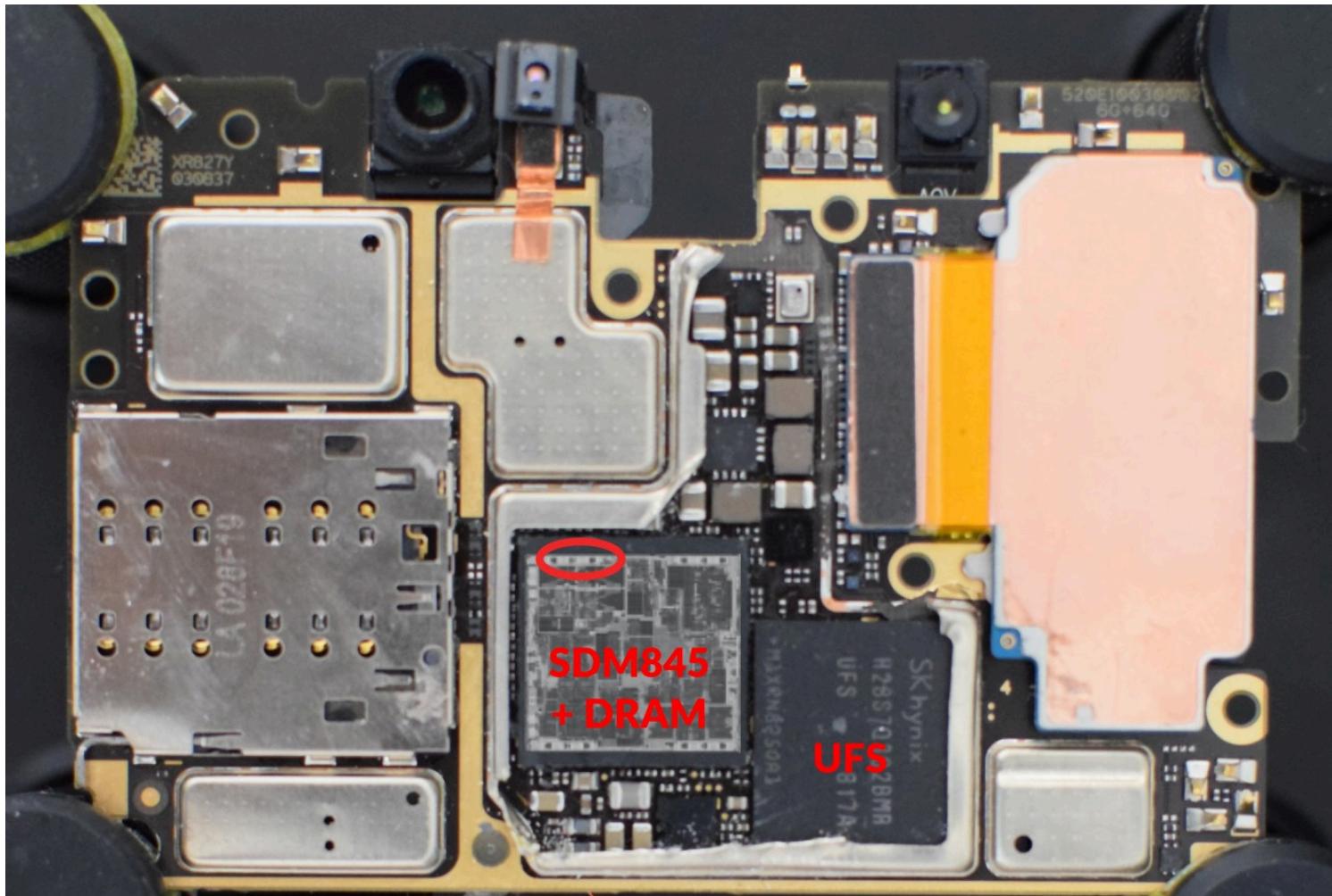
EMFI above SoC

Problem: DRAM stacked on SoC acts as a shield.



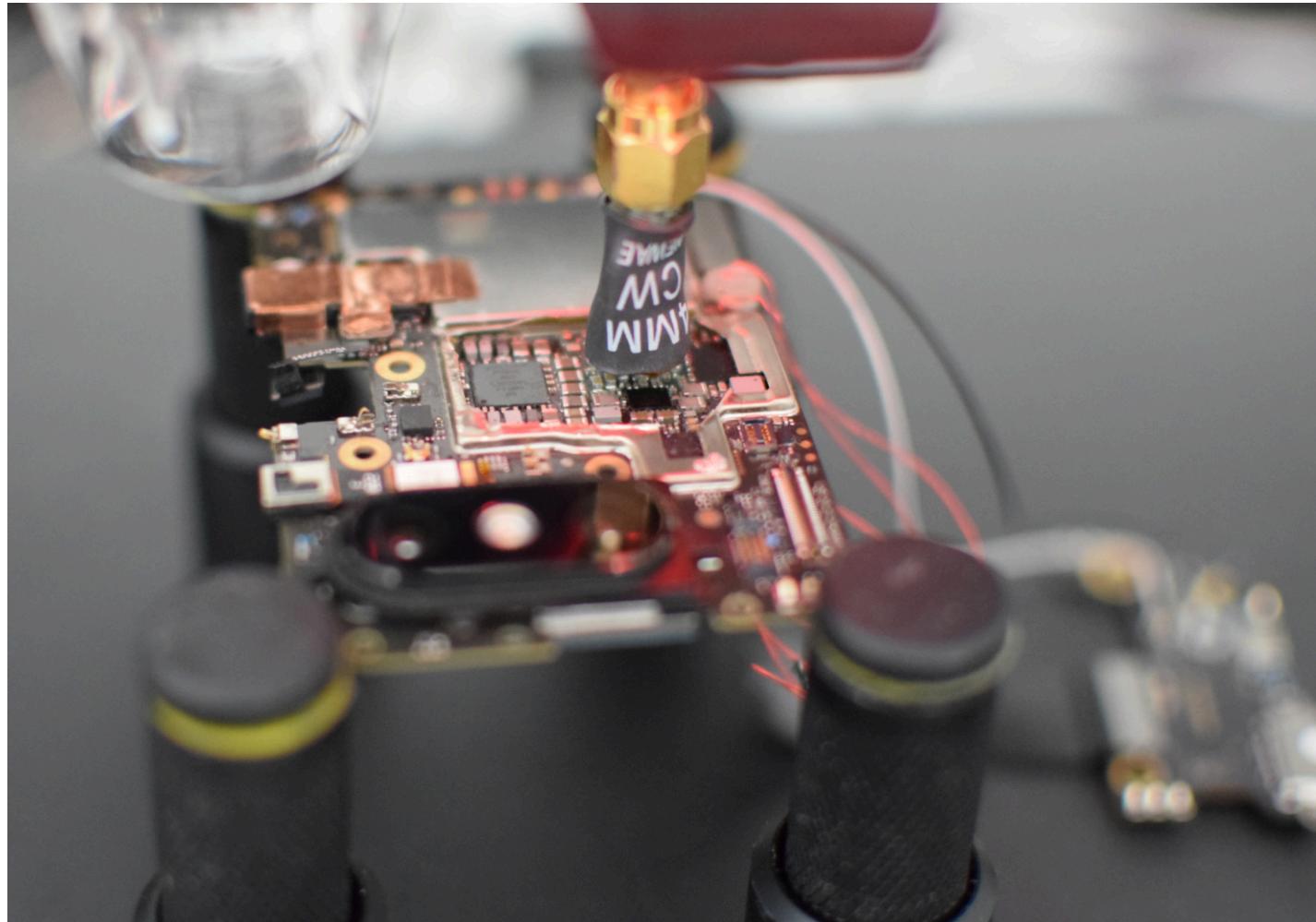
EMFI above SoC

Observation: crash on the side at 500V



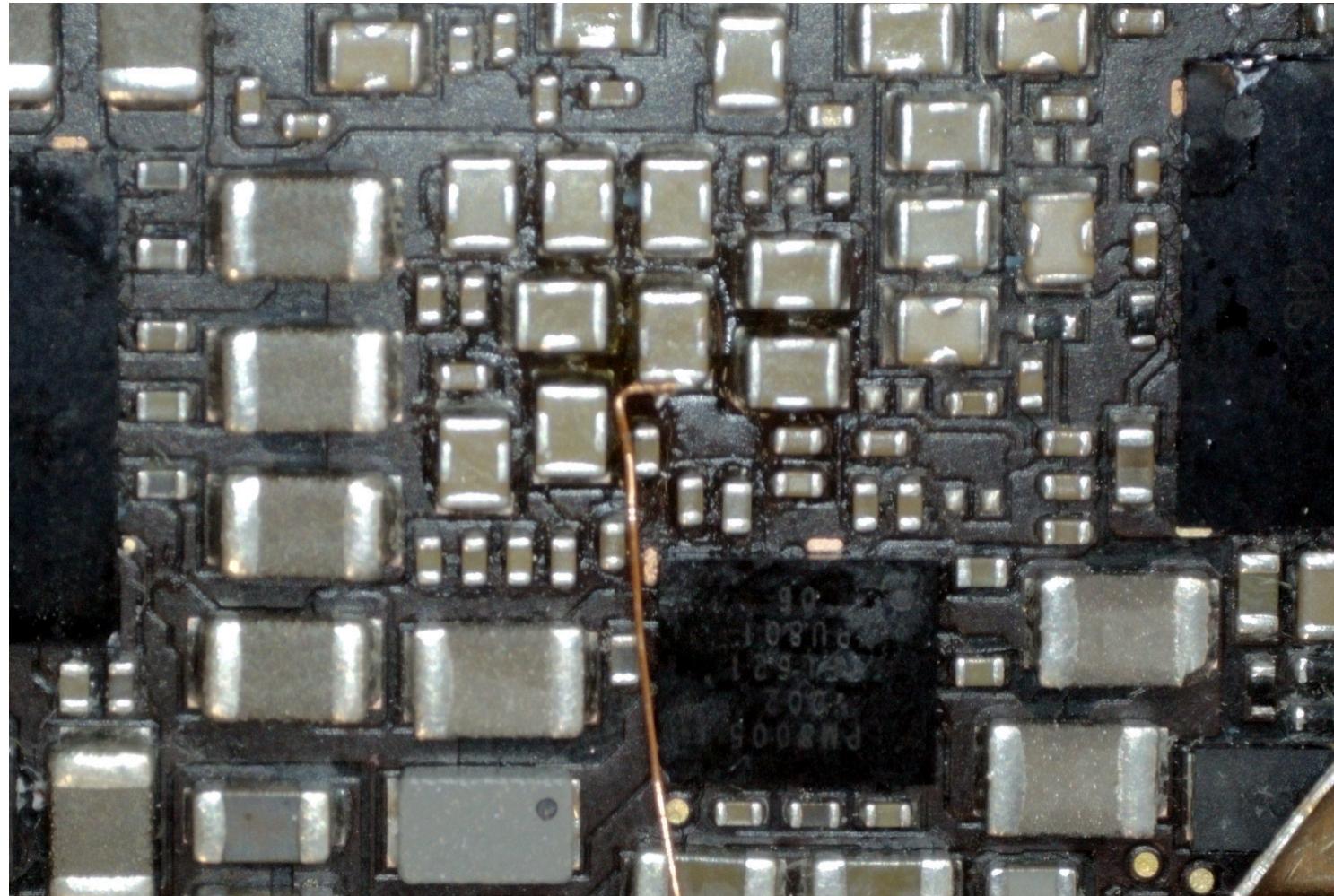
EMFI on capacitors

Problem: four-terminals capacitors have reduced EM sensibility.

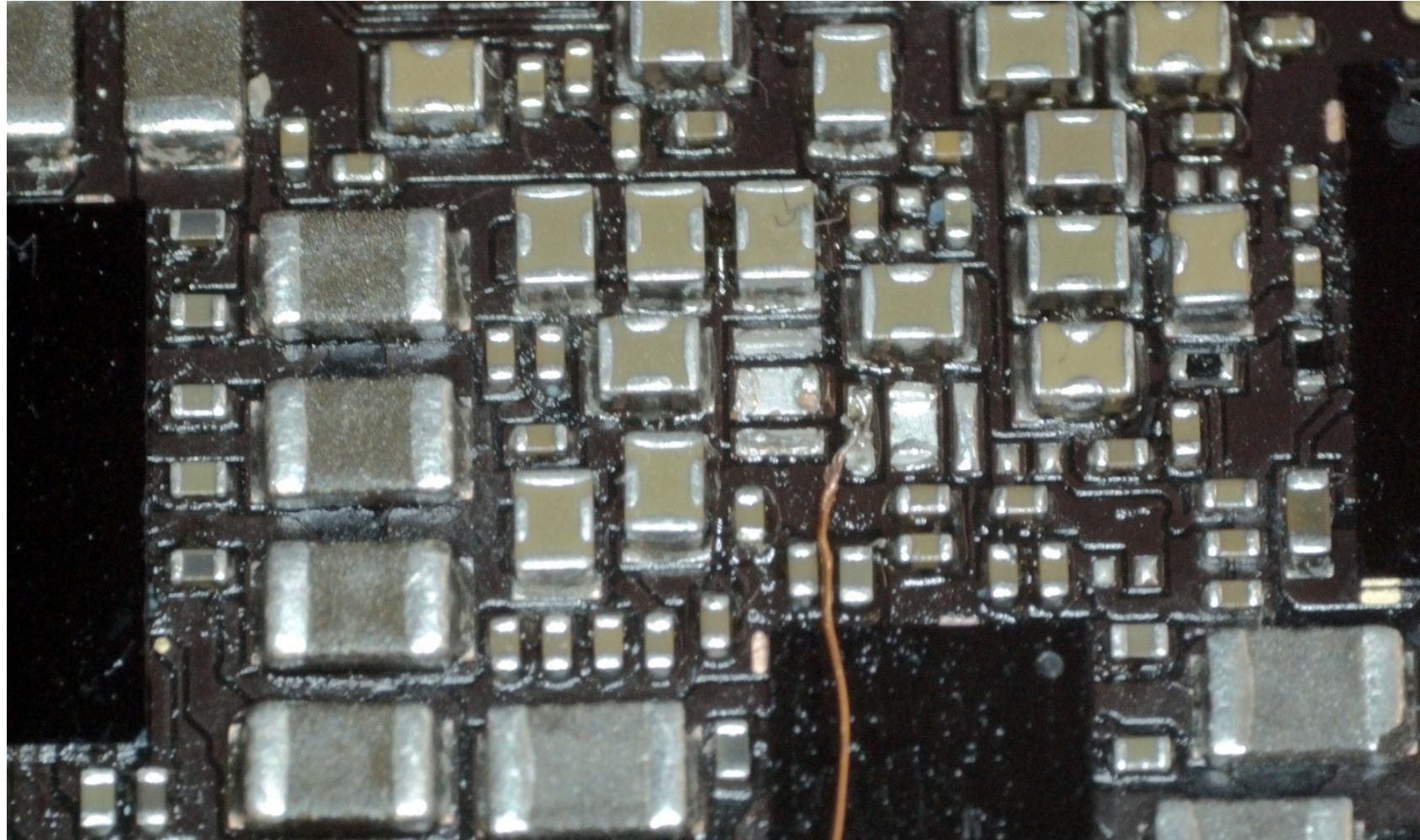


Power glitching with capacitors

Problem: no effects with ground crowbar glitch.



Power glitching without capacitors



Conclusion

- 7 unknown CMD response
- 4 read data error 0x0D (fault happens too early)
- 10 USB error
- no interesting faults and very low fault rate

Further static analysis reveals hardening (double checks, secured booleans, added jitter).

SDM845 has fault injection hardening that MSM8916 did not have.

Discussion

Bibliography

- Clément Fanjas and al., "PoP DRAM: A new EMFI approach based on EM-induced glitches on SoC", <https://cea.hal.science/cea-04948475v1>
- B. Kerler, unofficial Qualcomm Firehose / Sahara tools, <https://github.com/bkerler/edl>
- Qualcomm Glossary, postmarketOS Wiki,
https://wiki.postmarketos.org/wiki/Qualcomm_Glossary
- Niclas Kühnapfel and al., 2022, "EM-Fault It Yourself: Building a Replicable EMFI Setup for Desktop and Server Hardware", <https://arxiv.org/abs/2209.09835>
- Hector Marco, 2022, BlackHat Europe, "Vlind Glitch: A Blind VCC Glitching Technique to Bypass the Secure Boot of the Qualcomm MSM8916 Mobile SoC"



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